Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/803,083	KAKU ET AL.
Examiner	Art Unit
TUYEN T. NGUYEN	2832

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Class	Subclass	Date	Examiner
336	65, 83, 178, 180- 186	3/17/2005	TTN
379	349, 378	3/17/2005	TTN
379	402	3/17/2005	TTN
379	399.01	3/17/2005	TTN
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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